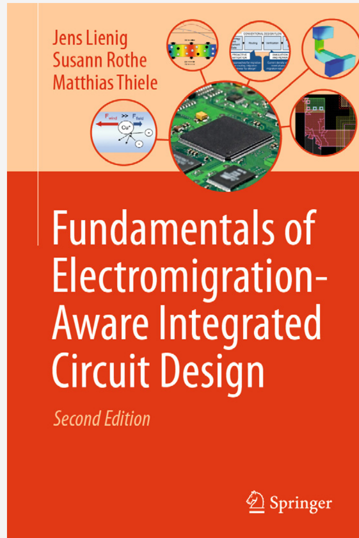

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J. Lienig, S. Rothe, M. Thiele

Fundamentals of Electromigration-Aware Integrated Circuit Design

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